

# Search Notes



Application/Control No.

10/710,747

Examiner

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Applicant(s)/Patent under Reexamination

OI, TAKESHI

Art Unit

3611

## SEARCHED

Class	Subclass	Date	Examiner
280	281.1 288.2 288.3	9/26/2005	MAA
UPDATE		9/25/06	MAA

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
SEE	ATTACH	9/25/06	MAA

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
US-PGPUB, JPO, EPO, USPAT	9/26/2005	MAA